



"electromagnetic scatterometry applied to in si

Search

[Advanced Scholar Search](#)
[Scholar Preferences](#)
[Scholar Help](#)

Scholar Results 1 - 2 of 2 for "**electromagnetic scatterometry applied to in situ metrology**". (0.06 seconds)

Tip: Try removing quotes from your search to get more results.

Electromagnetic scatterometry applied to in-situ metrology -
group of 3 »

[All articles](#) [Recent articles](#)

MS Yeung, E Barouch - Proceedings of SPIE, 2001 - link.aip.org

>/> **Electromagnetic scatterometry applied to in-situ metrology**. [Proceedings of SPIE 4344, 484 (2001)]. Michael S. Yeung, Eytan Barouch. Abstract. ...

Cited by 1 - [Web Search](#)

[CITATION] **Electromagnetic scatterometry applied to in-situ metrology** [4344-60]

MS Yeung, E Barouch - PROCEEDINGS-SPIE THE INTERNATIONAL SOCIETY FOR OPTICAL ..., 2001 - International Society for Optical Engineering; 1999

[Web Search](#) - [BL Direct](#)

"electromagnetic scatterometry appli

Search

[Google Home](#) - [About Google](#) - [About Google Scholar](#)

©2006 Google



"characterization of 3d resist patterns by mean

Search

[Advanced Scholar Search](#)
[Scholar Preferences](#)
[Scholar Help](#)

Scholar Results 1 - 2 of 2 for "characterization of 3d resist patterns by means of optical scatterometry".

Tip: Try removing quotes from your search to get more results.

Characterization of 3D resist patterns by means of optical scatterometry - group of 3 »

[All articles](#) [Recent articles](#)

J Bischoff, L Hutschenreuther, H Truckenbrodt, A ... - Proceedings of SPIE, 2003 - link.aip.org

>/> **Characterization of 3D resist patterns by means of optical scatterometry.**

[Proceedings of SPIE 3743, 49 (1999)]. Joerg Bischoff ...

[Web Search](#)

[CITATION] **Characterization of 3D resist patterns by means of optical scatterometry [3743-07]**

J Bischoff, L Hutschenreuther, H Truckenbrodt, A ... - PROCEEDINGS-SPIE THE INTERNATIONAL SOCIETY FOR OPTICAL ..., 1999 - SPIE INTERNATIONAL SOCIETY FOR OPTICAL

[Web Search](#) - [BL Direct](#)

"characterization of 3d resist pattern

Search

[Google Home](#) - [About Google](#) - [About Google Scholar](#)

©2006 Google